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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,344,498	09-1994	Inoue, Yuji	136/251
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	К	US-			
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## **NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U	D.G. Neerinck and T.J. Vink,"Depth profiling of thin ITO films by grazing incidence X-ray diffraction", Thin Solid Films 278 (1996) 12 - 17.					
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.